SONY

1/3-inch CCD Image Sensor for EIA Black-and-White Video Camera

Description

The ICX058AL is an interline CCD solid-state image sensor suitable for EIA black-and-white video cameras. High sensitivity and low dark current are achieved through the adoption of HAD (Hole-Accumulation Diode) sensors.

This chip features a field period readout system and an electronic shutter with variable charge-storage time.

Features

• High resolution, high sensitivity and low dark current

1/3-inch format

768 (H) \times 494 (V) approx. 380K pixels

811 (H) \times 508 (V) approx. 410K pixels

Horizontal (H) direction: Front 3 pixels, rear 40 pixels

Front 12 pixels, rear 2 pixels

6.00mm (H) × 4.96mm (V)

6.35µm (H) × 7.40µm (V)

Vertical 1 (even field only)

Vertical (V) direction:

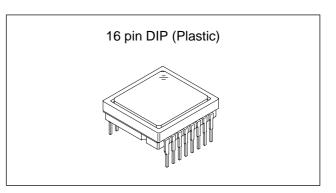
Horizontal 22

Silicon

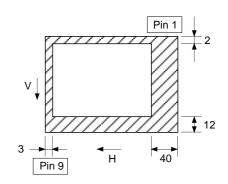
- Continuous variable-speed shutter 1/60s (Typ.), 1/100s to 1/10000s
- Low smear
- Excellent antiblooming characteristics
- Horizontal register: 5V drive
- Reset gate: 5V drive

Device Structure

- Optical size:
- Number of effective pixels:
- Number of total pixels:
- Interline CCD image sensor
- Chip size:
- Unit cell size:
- Optical black:
- Number of dummy bits:
- Substrate material:



ICX058AL

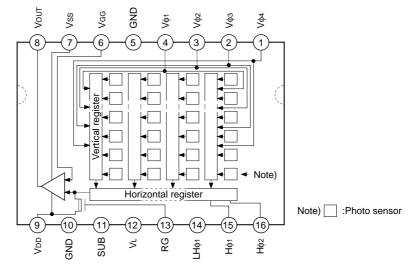


Optical black position (Top View)

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Block Diagram and Pin Configuration

(Top View)



Pin Description

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	Vø4	Vertical register transfer clock	9	Vdd	Output amplifier drain supply
2	Vфз	Vertical register transfer clock	10	GND	GND
3	Vø2	Vertical register transfer clock	11	SUB	Substrate (Overflow drain)
4	Vφ1	Vertical register transfer clock	12	VL	Protective transistor bias
5	GND	GND	13	RG	Reset gate clock
6	Vgg	Output amplifier gate bias	14	LH _{\$1}	Horizontal register final stage transfer clock
7	Vss	Output amplifier source	15	Hφ1	Horizontal register transfer clock
8	Vout	Signal output	16	Hø2	Horizontal register transfer clock

Absolute Maximum Ratings

	Item	Ratings	Unit	Remarks
Substrate voltage SUB – C	GND	-0.3 to +55	V	
Supply voltage	Vdd, Vout, Vss – GND	-0.3 to +18	V	
Supply voltage	Vdd, Vout, Vss – SUB	-55 to +10	V	
	Vφ1, Vφ2, Vφ3, Vφ4 – GND	-15 to +20	V	
Vertical clock input voltage	Vφ1, Vφ2, Vφ3, Vφ4 – SUB	to +10	V	
Voltage difference betwee	n vertical clock input pins	to +15	V	*1
Voltage difference betwee	n horizontal clock input pins	to +17	V	
Ηφ1, Ηφ2 – Vφ4		-17 to +17	V	
Ηφ1, Ηφ2, LΗφ1, RG, Vgg –	GND	-10 to +15	V	
Ηφ1, Ηφ2, LΗφ1, RG, Vgg –	SUB	-55 to +10	V	
VL-SUB		-65 to +0.3	V	
Vφ1, Vφ2, Vφ3, Vφ4, VDD, VC	DUT – VL	-0.3 to +30	V	
RG – VL		-0.3 to +24	V	
Vgg, Vss, Hø1, Hø2, LHø1 -	- VL	-0.3 to +20	V	
Storage temperature		-30 to +80	°C	
Operating temperature		-10 to +60	°C	

*1 +27V (Max.) when clock width < 10μ s, clock duty factor < 0.1%.

Bias Conditions

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain voltage	Vdd	14.55	15.0	15.45	V	
Output amplifier gate voltage	Vgg	3.8	4.2	4.65	V	
Output amplifier source	Vss		ounded w 20Ω resist			±5%
Substrate voltage adjustment range	Vsub	9.0		18.5	V	*1
Fluctuation range after substrate voltage adjustment	ΔVsub	-3		+3	%	
Reset gate clock voltage adjustment range	Vrgl	1.0		4.0	V	*1, *6
Fluctuation range after reset gate clock voltage adjustment	ΔV rgl	-3		+3	%	
Protective transistor bias	VL		*2	1		

DC Characteristics

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain current	Idd		5		mA	
Input current	lin1			1	μA	*3
Input current	lin2			10	μA	*4

^{*1} Indications of substrate voltage (Vsub) · reset gate clock voltage (VRGL) setting value.

The setting values of substrate voltage and reset gate clock voltage are indicated on the back of the image sensor by a special code. Adjust substrate voltage (Vsub) and reset gate clock voltage (VRGL) to the indicated voltage. Fluctuation range after adjustment is $\pm 3\%$.

Vsub code one character indication

one character indication

 $\Box \Box \\ \uparrow \uparrow$

VRGL code VSUB code

Code and optimal setting correspond to each other as follows.

Vrgl code	1	2	3	4	5	6	7
Optimal setting	1.0	1.5	2.0	2.5	3.0	3.5	4.0

VRGL code

Vsub code	E	f	G	h	J	К	L	m	Ν	Ρ	Q	R	S	Т	U	V	W	Х	Υ	Ζ
Optimal setting	9.0	9.5	10.0	10.5	11.0	11.5	12.0	12.5	13.0	13.5	14.0	14.5	15.0	15.5	16.0	16.5	17.0	17.5	18.0	18.5

<Example> "5L" \rightarrow VRGL = 3.0V VSUB = 12.0V

*2 VL setting is the VvL voltage of the vertical transfer clock waveform.

- *3 1) Current to each pin when 18V is applied to VDD, VOUT, Vss and SUB pins, while pins that are not tested are grounded.
 - 2) Current to each pin when 20V is applied sequentially to Vφ1, Vφ2, Vφ3 and Vφ4 pins, while pins that are not tested are grounded. However, 20V is applied to SUB pin.
 - 3) Current to each pin when 15V is applied sequentially to RG, LHφ1, Hφ1, Hφ2 and VGG pins, while pins that are not tested are grounded. However, 15V is applied to SUB pin.
 - 4) Current to VL pin when 30V is applied to Vφ1, Vφ2, Vφ3, Vφ4, VDD and VOUT pins or when, 24V is applied to RG pin or when, 20V is applied to VGG, VSS, Hφ1, Hφ2 and LHφ1 pins, while VL pin is grounded. However, GND and SUB pins are left open.
- ^{*4} Current to SUB pin when 55V is applied to SUB pin, while pins that are not tested are grounded.

Clock Voltage Conditions

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Readout clock voltage	Vvт	14.55	15.0	15.45	V	1	
	Vvh1, Vvh2	-0.05	0	0.05	V	2	Vvн = (Vvн1 + Vvн2)/2
	Vvнз, Vvн4	-0.2	0	0.05	V	2	
	Vvl1, Vvl2, Vvl3, Vvl4	-9.0	-8.5	-8.0	V	2	$V_{VL} = (V_{VL3} + V_{VL4})/2$
	Vφv	7.8	8.5	9.05	V	2	$V\phi = V + n - V + n$ (n = 1 to 4)
Vertical transfer clock	I Vvh1 – Vvh2 I			0.1	V	2	
voltage	Vvнз — Vvн	-0.25		0.1	V	2	
	Vvн4 — Vvн	-0.25		0.1	V	2	
	Vvнн			0.5	V	2	High-level coupling
	Vvhl			0.5	V	2	High-level coupling
	Vvlh			0.5	V	2	Low-level coupling
	Vvll			0.5	V	2	Low-level coupling
Horizontal transfer	Vфн, Vфlн	4.75	5.0	5.25	V	3	*5
clock voltage	Vhl, Vlhl	-0.05	0	0.05	V	3	*5
Reset gate clock	Vørg	4.5	5.0	5.5	V	4	*6
voltage	Vrglh – Vrgll			0.8	V	4	Low-level coupling
Substrate clock voltage	Vфsuв	22.5	23.5	24.5	V	5	

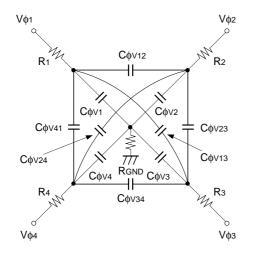
*5 The horizontal final stage transfer clock input pin LHφ1 is connected to the horizontal transfer clock input pin Hφ1.

*6 The reset gate clock voltage need not be adjusted when reset gate clock is driven when the specifications are as given below. In this case, the reset gate clock voltage setting indicated on the back of the image sensor has not significance.

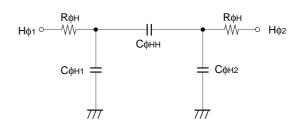
Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Reset gate clock	Vrgl	-0.2	0	0.2	V	4	
voltage	Vørg	8.5	9.0	9.5	V	4	

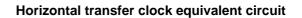
Clock Equivalent Circuit Constant

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Capacitance between vertical transfer	Cφν1, Cφν3		1000		pF	
clock and GND	C φv2, C φv4		560		pF	
	Сфv12, Сфv34		470		pF	
Capacitance between vertical transfer	Сфv23, Сфv41		330		pF	
clocks	Сф∨13		220		pF	
	Сф∨24		100		pF	
Capacitance between horizontal transfer clock and GND	Сфн1, Сфн2		47		pF	
Capacitance between horizontal transfer clocks	Сфнн		43		pF	
Capacitance between horizontal final stage transfer clock and GND	Сфін		8		pF	
Capacitance between reset gate clock and GND	Сфра		8		pF	
Capacitance between substrate clock and GND	Сфѕив		270		pF	
Vertical transfer clock series resistor	R1, R2, R3, R4		80		Ω	
Vertical transfer clock ground resistor	Rgnd		15		Ω	
Horizontal transfer clock series resistor	Rфн		15		Ω	



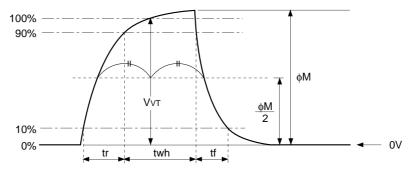
Vertical transfer clock equivalent circuit



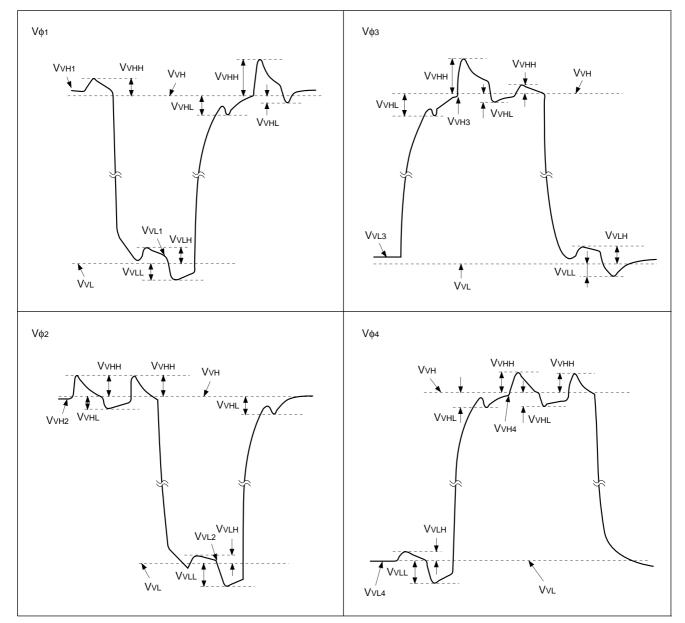


Drive Clock Waveform Conditions

(1) Readout clock waveform

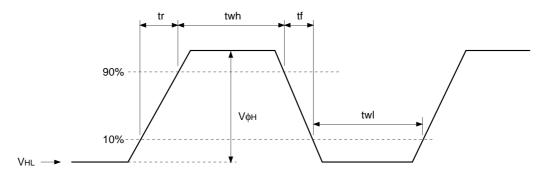


(2) Vertical transfer clock waveform

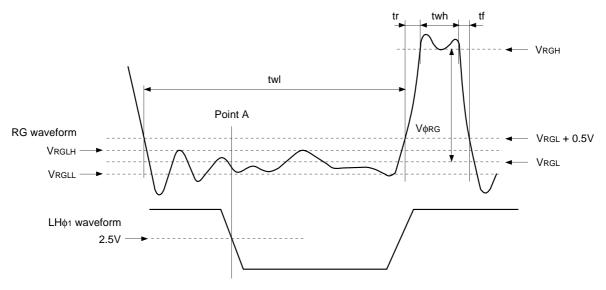


$$\begin{split} V_{VH} &= (V_{VH1} + V_{VH2})/2\\ V_{VL} &= (V_{VL3} + V_{VL4})/2\\ V_{\varphi V} &= V_{VHN} - V_{VLN} \ (n=1 \ to \ 4) \end{split}$$

(3) Horizontal transfer clock waveform



(4) Reset gate clock waveform



VRGLH is the maximum value and VRGLL is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG.

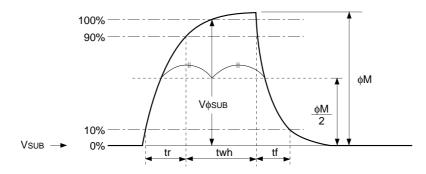
In addition, VRGL is the average value of VRGLH and VRGLL.

VRGL = (VRGLH + VRGLL)/2

Assuming VRGH is the minimum value during the interval twh, then:

 $V\phi RG = VRGH - VRGL$

(5) Substrate clock waveform



Clock Switching Characteristics

Note) Because the horizontal final stage transfer clock $LH\phi_1$ is connected to the horizontal transfer clock $H\phi_1$, specifications will be the same as $H\phi_1$.

	ltem	Symbol		twh			twl			tr			tf		Unit	Remarks
	nom	Cymbol	Min.	Тур.	Max.		Remarks									
Readout clock		VT	2.3	2.5						0.5			0.5		μs	During readout
Vert cloc	tical transfer k	Vφ1, Vφ2, Vφ3, Vφ4										15		250	ns	*1
_ <u>×</u>		Ηφ1, LHφ1	18	24		19.5	26			10	17.5		10	17.5		*2
onta r clo	imaging	Hø2	21	26		19	24			10	15		10	15	ns	2
Horizontal transfer clock	During parallel-serial	Hø1, LHø1		5.38						0.01			0.01			
ta T	conversion	Hø2					5.38			0.01			0.01		μs	
Res	et gate clock	φRG	11	13			51			3			3		ns	
Sub	strate clock	фѕив	1.5	1.8							0.5			0.5	μs	During drain charge

*1 When vertical transfer clock driver CXD1250 is used.

*2 tf \geq tr - 2ns, and the cross-point voltage (VcR) for the H $\phi_1 \cdot$ LH ϕ_1 rising side of the H $\phi_1 \cdot$ LH ϕ_1 and H ϕ_2 waveforms must be at least 2.5V.

Item	Symbol		two		Unit	Remarks	
item	Symbol	Min.	Тур.	Max.	Unit	Remarks	
Horizontal transfer clock	Ηφ1 · LΗφ1, Ηφ2	16	20		ns	*3	

*3 The overlap period for twh and twl of horizontal transfer clocks $H\phi_1\cdot LH\phi_1$ and $H\phi_2$ is two.

Image Sensor Characteristics

(Ta =	25°C)
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Item	Symbol	Min.	Тур.	Max.	Unit	Measurement method	Remarks
Sensitivity	S	240	300		mV	1	
Saturation signal	Vsat	600			mV	2	Ta = 60°C
Smear	Sm		0.009	0.015	%	3	
Video signal shading	SH			20	%	4	Zone 0 and I
				25	%	4	Zone 0 to II'
Dark signal	Vdt			2	mV	5	Ta = 60°C
Dark signal shading	ΔVdt			1	mV	6	Ta = 60°C
Flicker	F			2	%	7	
Lag	Lag			0.5	%	8	

Zone Definition of Video Signal Shading

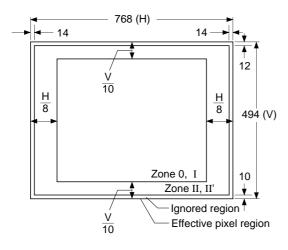


Image Sensor Characteristics Measurement Method

O Measurement conditions

- 1) In the following measurements, the substrate voltage and the reset gate clock voltage are set to the values indicated on the device, and the device drive conditions are at the typical values of the bias and clock voltage conditions.
- 2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black (OB) level is used as the reference for the signal output, and the value measured at point [*A] in the drive circuit example is used.

◎ Definition of standard imaging conditions

1) Standard imaging condition I:

Use a pattern box (luminance 706cd/m², color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter and image at F8. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity.

2) Standard imaging condition II:

Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter. The luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm.

1. Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/250s, measure the signal output (Vs) at the center of the screen and substitute the value into the following formula.

$$S = Vs \times \frac{250}{60} [mV]$$

2. Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with average value of the signal output, 200mV, measure the minimum value of the signal output.

3. Smear

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity to 500 times the intensity with average value of the signal output, 200mV. When the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value VSm [mV] of the signal output and substitute the value into the following formula.

 $Sm = \frac{VSm}{200} \times \frac{1}{500} \times \frac{1}{10} \times 100 \text{ [\%] (1/10V method conversion value)}$

4. Video signal shading

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity so that the average value of the signal output is 200mV. Then measure the maximum (Vmax [mV]) and minimum (Vmin [mV]) values of the signal output and substitute the values into the following formula.

 $SH = (Vmax - Vmin)/200 \times 100 [\%]$

5. Dark signal

Measure the average value of the signal output (Vdt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

6. Dark signal shading

After measuring 5, measure the maximum (Vdmax [mV]) and minimum (Vdmin [mV]) values of the dark signal output and substitute the values into the following formula.

 $\Delta Vdt = Vdmax - Vdmin [mV]$

7. Flicker

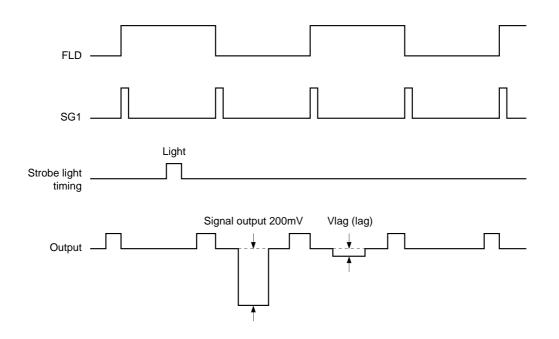
Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the signal output is 200mV, and then measure the difference in the signal level between fields (Δ Vf [mV]). Then substitute the value into the following formula.

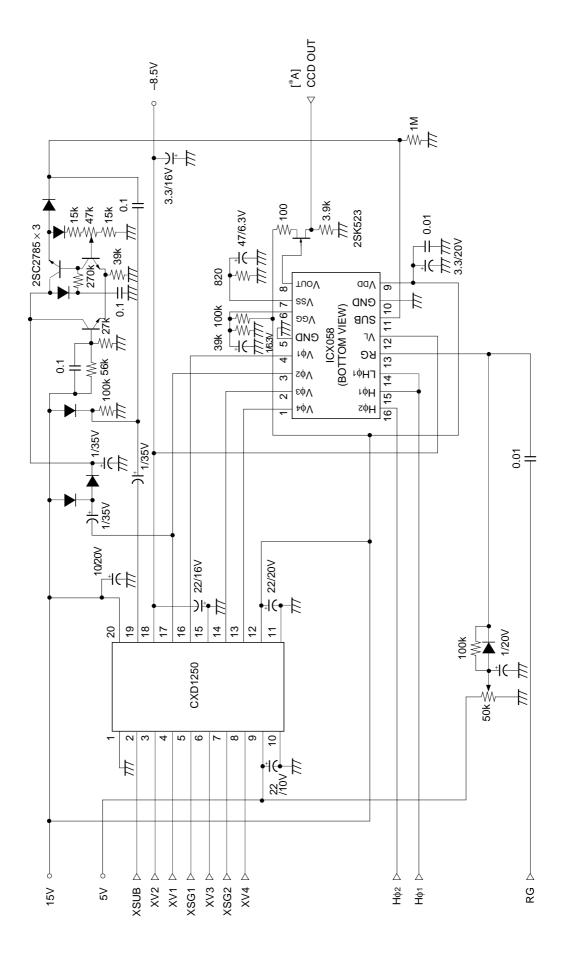
 $F = (\Delta V f/200) \times 100 [\%]$

8. Lag

Adjust the signal output value generated by strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Vlag). Substitute the value into the following formula.

Lag = (Vlag/200) × 100 [%]

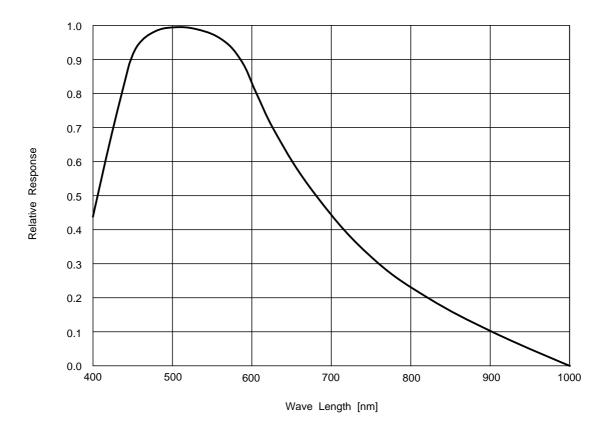


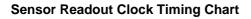


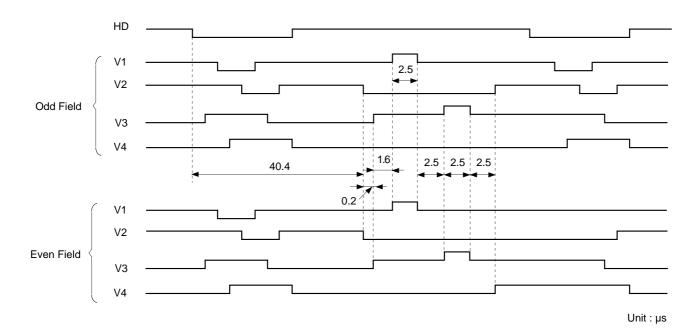
Drive Circuit

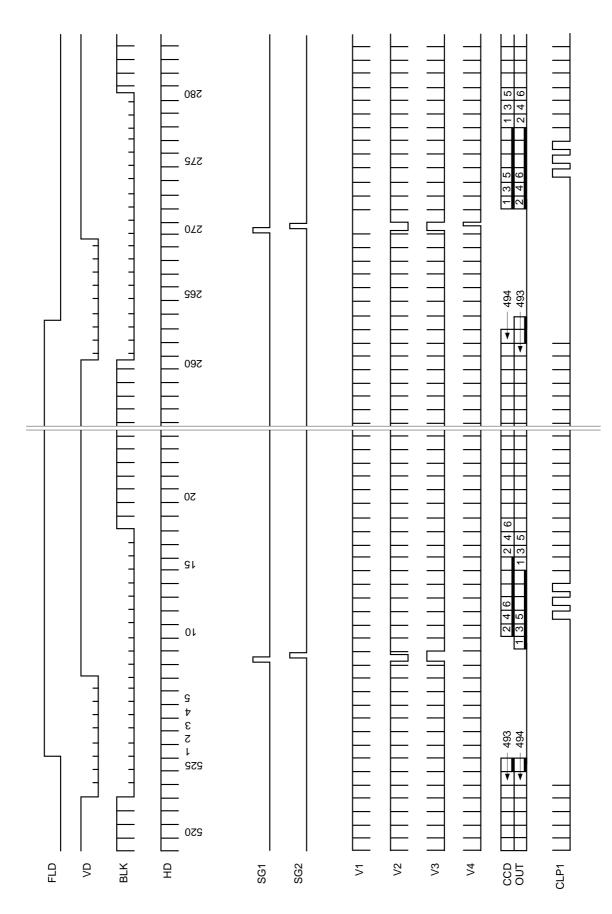
Spectral Sensitivity Characteristics

(Includes lens characteristics, excludes light source characteristics)

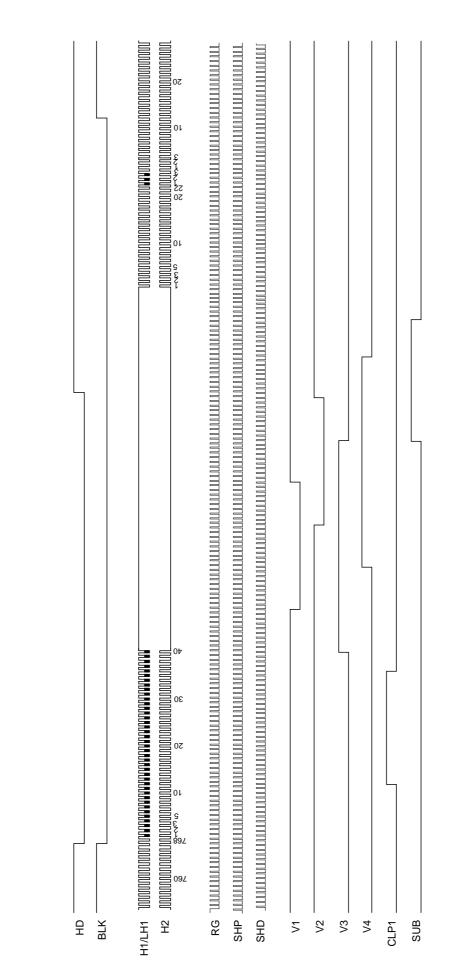












Notes on Handling

1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.
- 3) Dust and dirt protection
 - a) Operate in clean environments (around class 1000 is appropriate).
 - b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
 - c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
 - d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
 - e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.
- 4) Do not expose to strong light (sun rays) for long periods.
- 5) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- 6) CCD image sensors are precise optical equipment that should not be subject to mechanical shocks.

